

Si-microstrip LGAD detectors for cosmic-ray space-borne instruments

Martina Savinelli⁵

on behalf of the PTSD team: M. Barbanera², E. Cavazzuti¹, M. Duranti², V. Formato⁴, J. Hu², M. Mergè¹, M. Miliucci¹, M. Movileanu², B. Negri¹, A. Oliva³, V. Vagelli ¹⁻²

1) Italian Space Agency

2) INFN – Sezione di Perugia

3) INFN – Sezione di Bologna

4) INFN – Sezione di Tor Vergata

5) Università degli Studi di Perugia

+ many thanks to L. Pacini (INFN – Sezione di Firenze)

PRIN: Pentadimensional Tracking Space Detector

Collaboration:

- Italian Space Agency
- INFN

Goal:

Adapt the LGAD to the spatial environment by means of special geometries to keep under control the electrical capacity while maintaining unchanged the temporal performance.

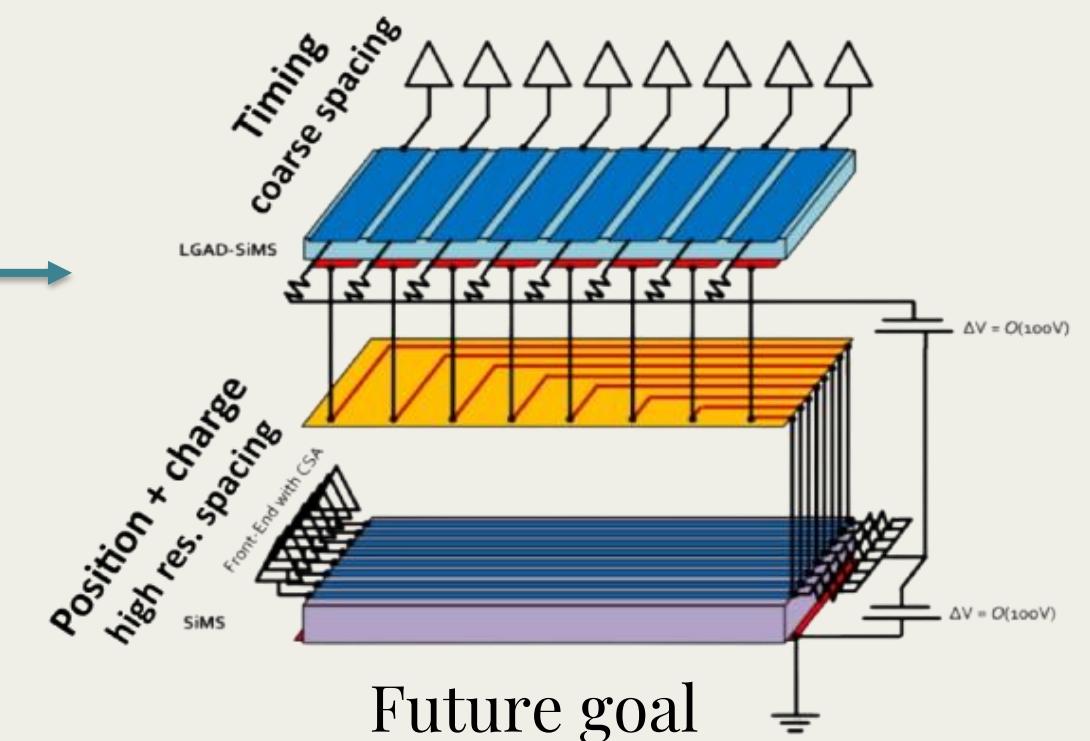
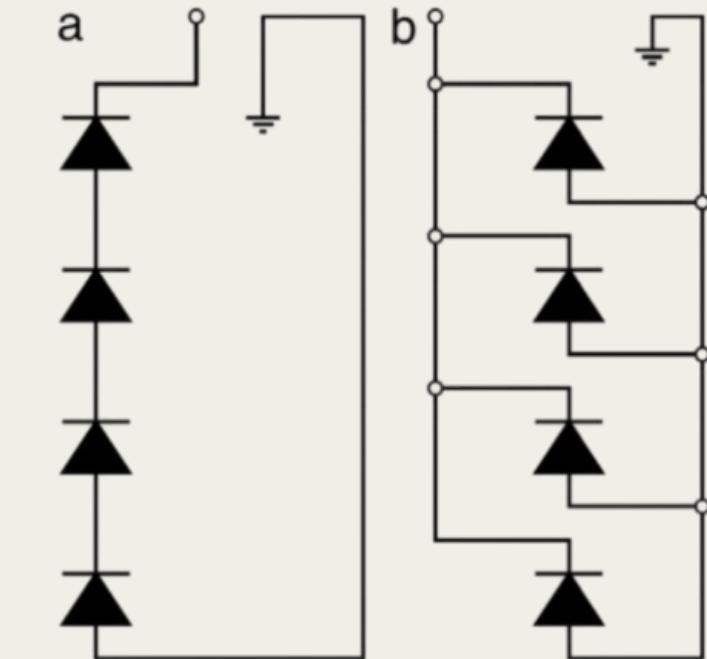
For SiPMs:

- a) «serial» readout:
 - ✗ bias voltage doesn't scale with the number of sensors
 - ✓ total capacity decreases with increasing number of sensors
- b) Traditional «parallel» readout:
 - ✓ bias voltage independent on number of sensors
 - ✗ total capacitance increase with the increasing number of sensors

Can we do the same for LGADs? →

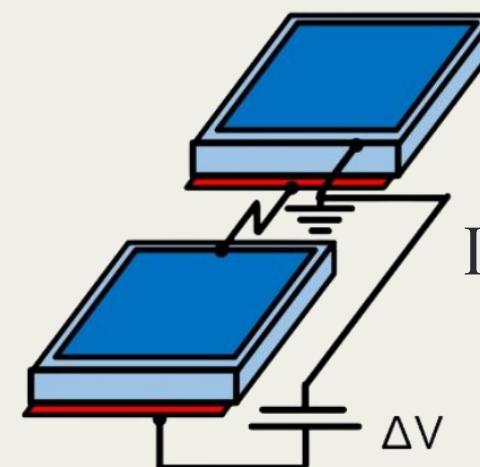
$$ENC_{\text{preamp}} \propto C_{\text{tot}}$$

$$C_{\text{tot}} = \left(\frac{1}{C_1} + \frac{1}{C_2} \right)^{-1}$$



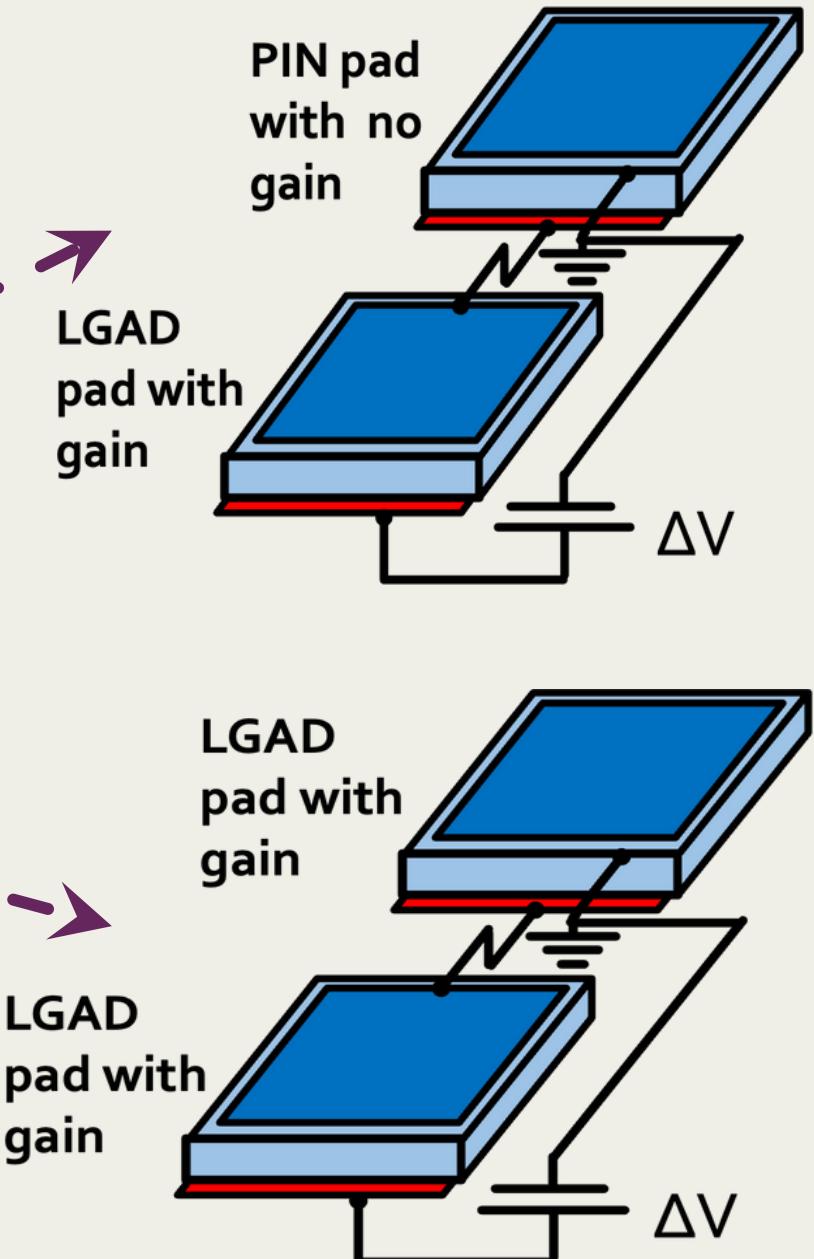
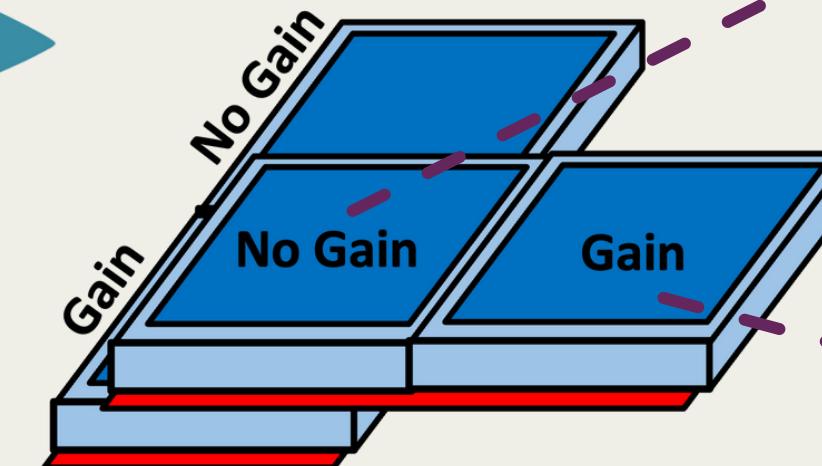
LAB TEST

We started with the characterization (Thanks to F.Moscattelli) of 7 pairs of PIN-LGAD test structures (FBK from the MoveIT project)

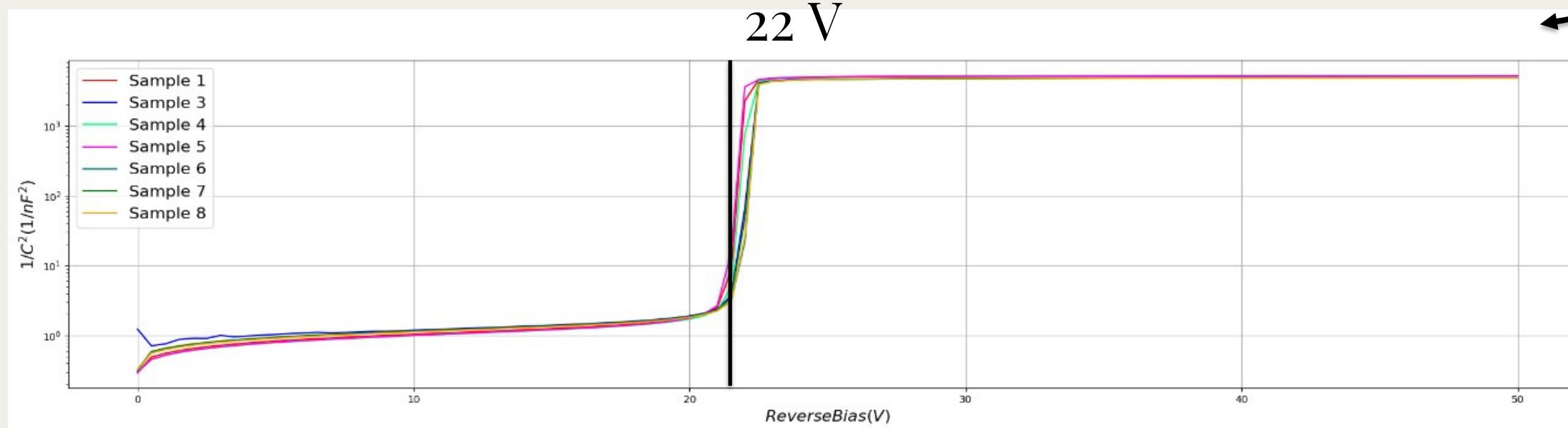
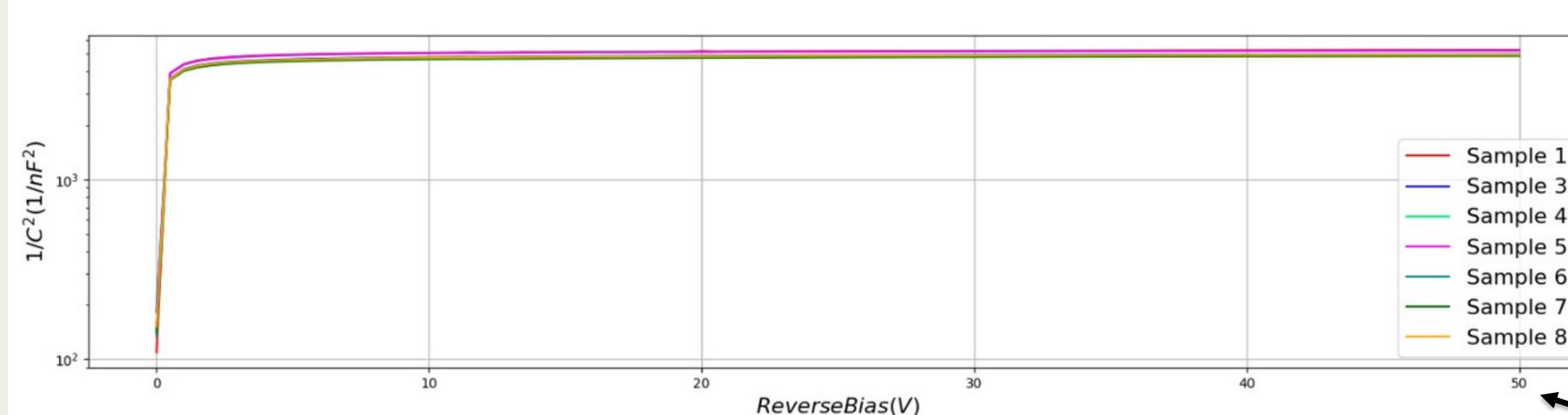


Initial prototype

Then two devices have been glued together with two little drops of connective glue



LAB TEST



$$\frac{1}{d} \propto C \propto \frac{1}{\sqrt{V}}$$

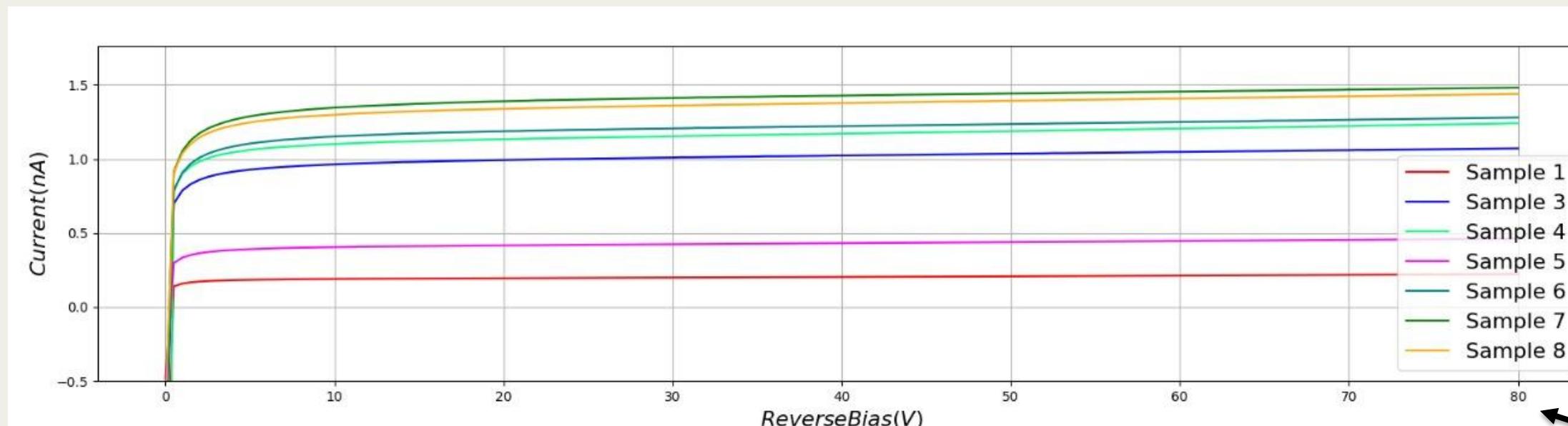
-CV:

PIN $\sim 13.9 - 14.7 \pm 0.2$ pF

LGAD $\sim 13.9 - 14.7 \pm 0.2$ pF

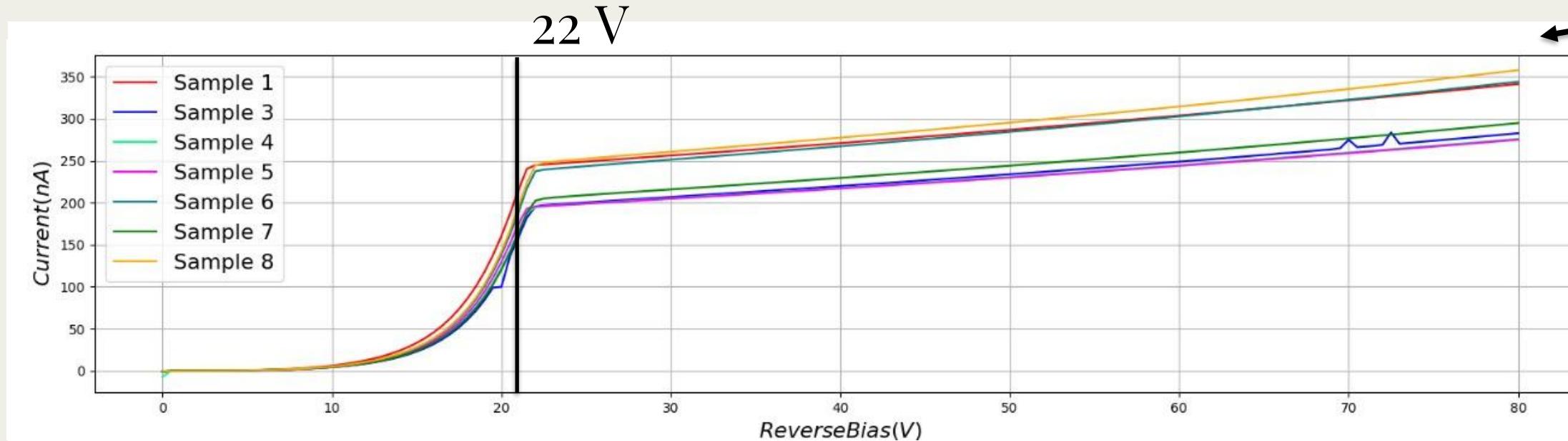
LAB TEST

$$i_m = -qvE_w$$



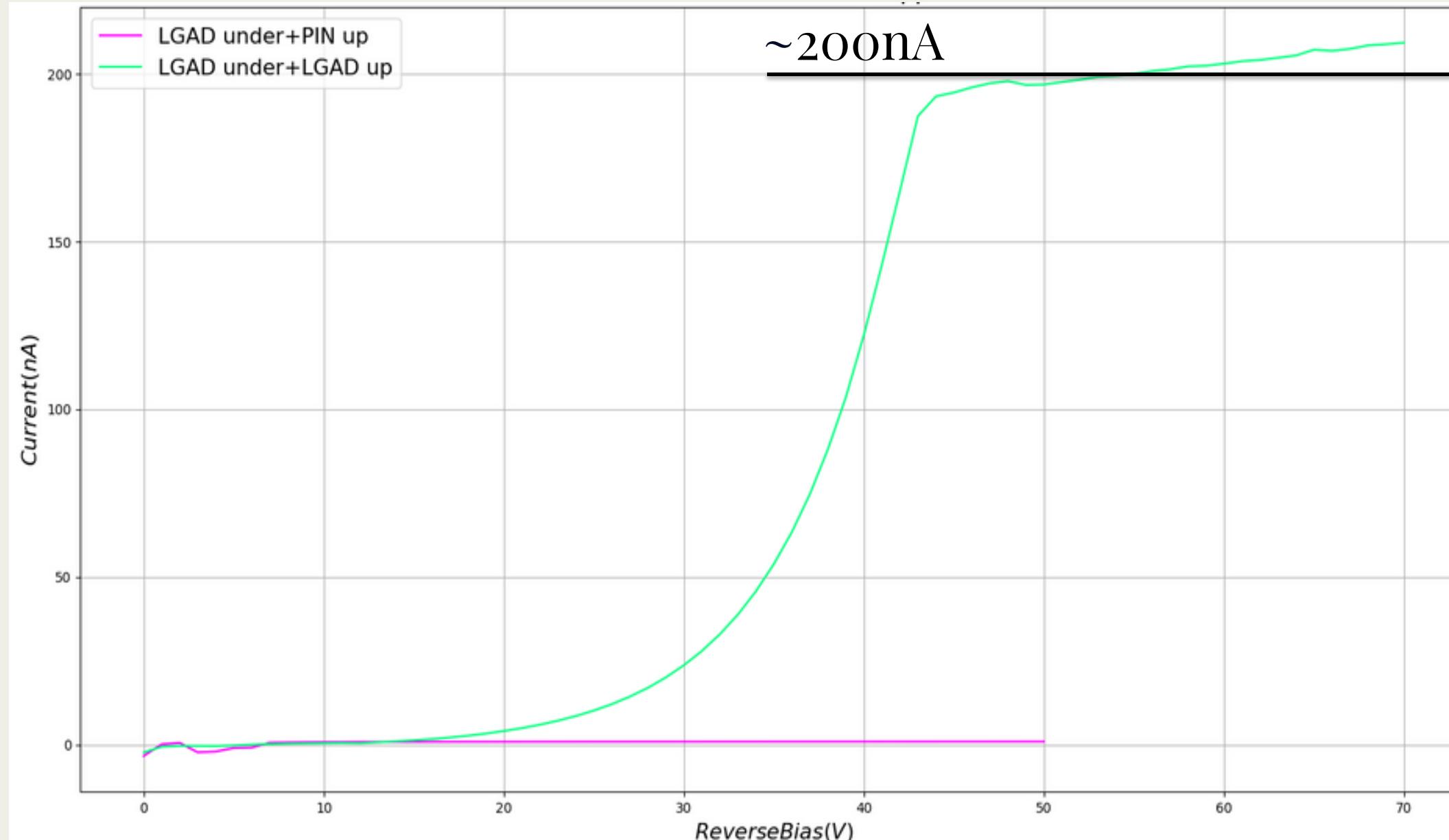
-IV:

PIN 0.5-1.5 nA



LGAD ~ 250-350 nA

MEASUREMENTS MADE ON THE FINAL DEVICE:



I-V:

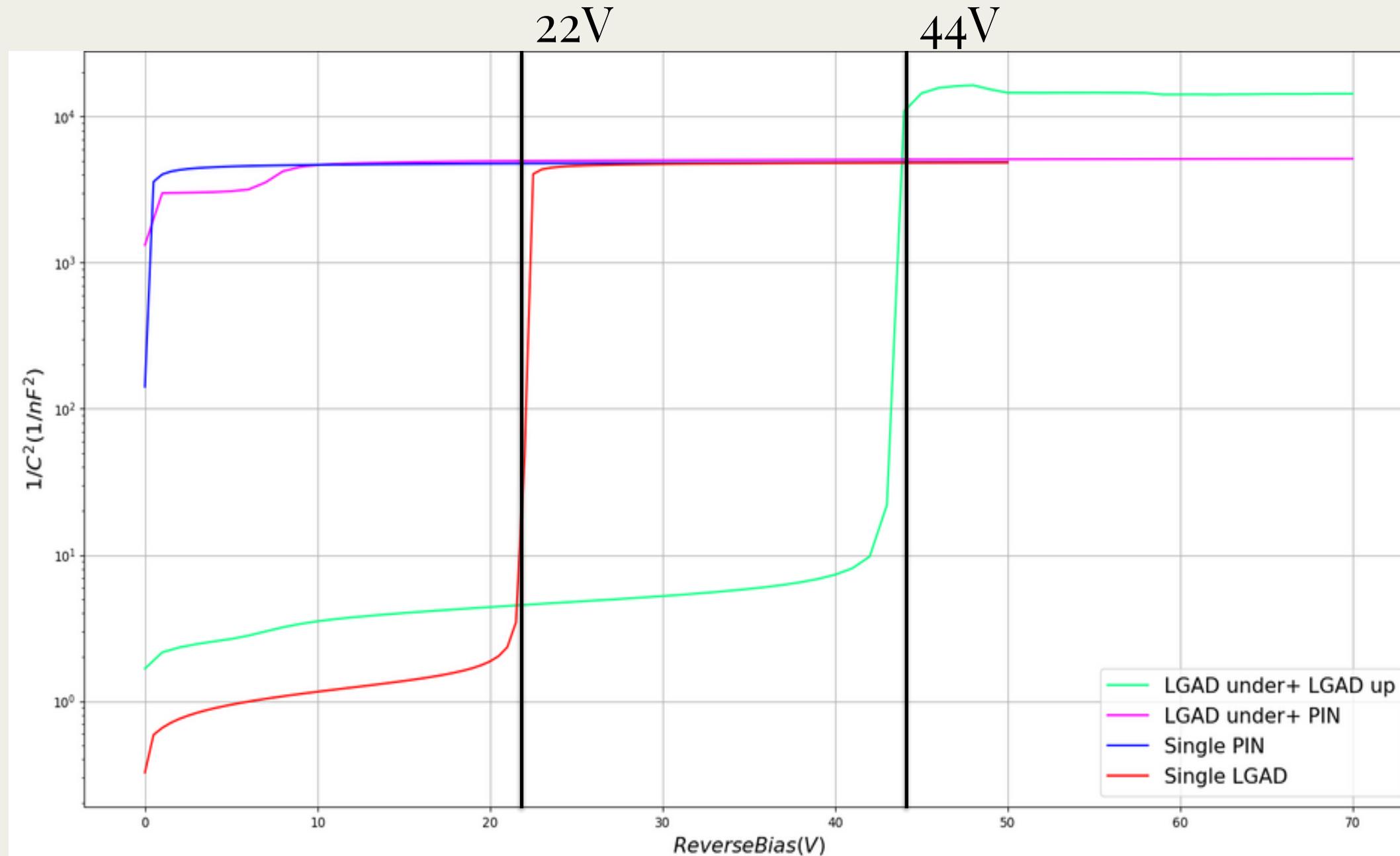
LGAD-LGAD \sim 200nA,

PIN-LGAD \sim 1nA

Both work!

Since the current flowing through the devices must be the same, the total leakage current is determined by the device with the lowest current. In the LGAD-LGAD case, it is even lower than expected.

MEASUREMENTS MADE ON THE FINAL DEVICE:



C-V:

LGAD $\sim 13.9 - 14.7 \pm 0.2$ pF

PIN $\sim 13.9 - 14.7 \pm 0.2$ pF

LGAD-LGAD $\sim 8.3 \pm 0.2$ pF

PIN-LGAD $\sim 13.9 - 14.7 \pm 0.2$ pF

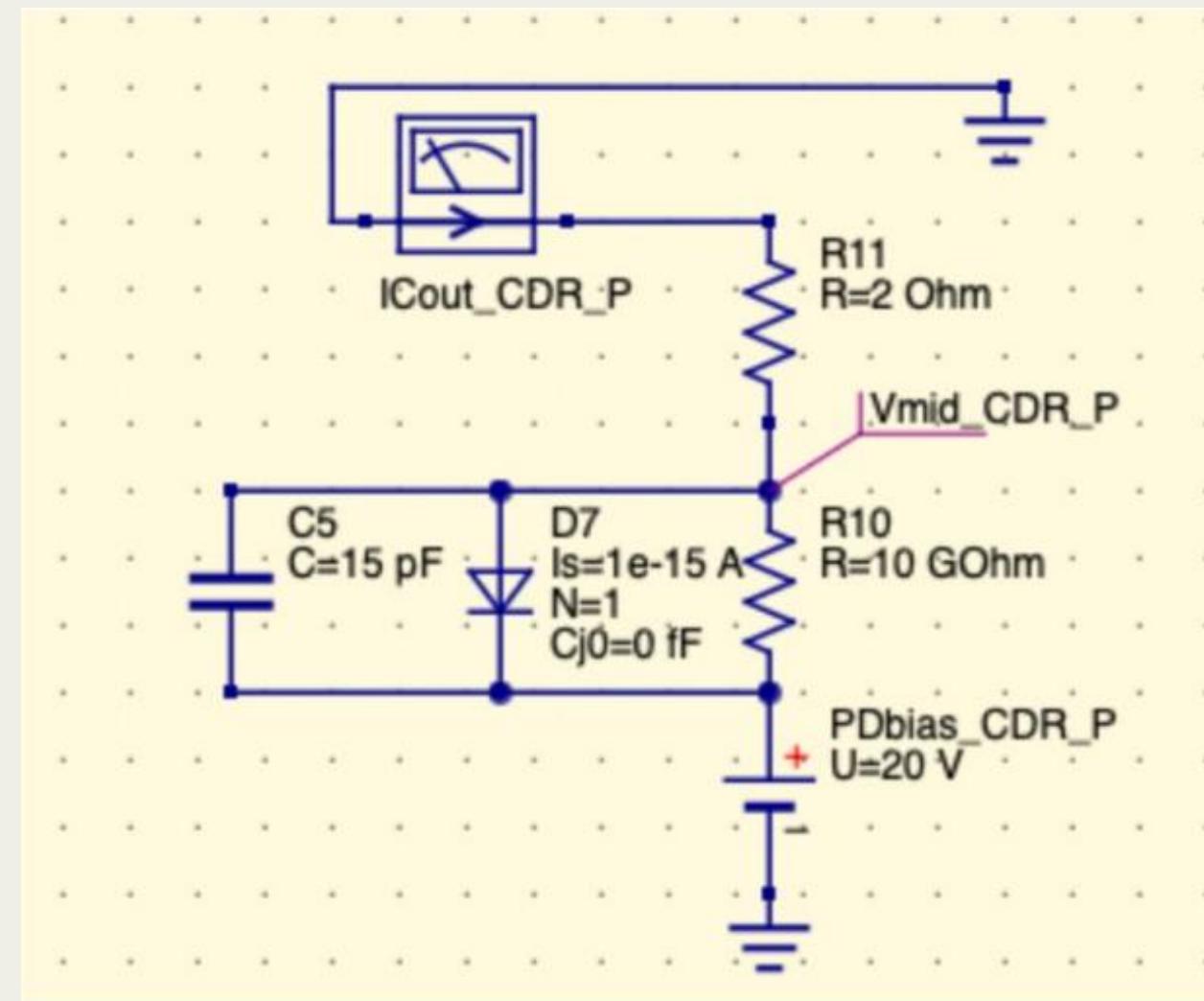
For the LGAD-LGAD case everything seems to work, even though we were expecting to measure 7pF and we measured 8pF. To be understood.

For the PIN-LGAD case we hadn't thought but the result is obvious

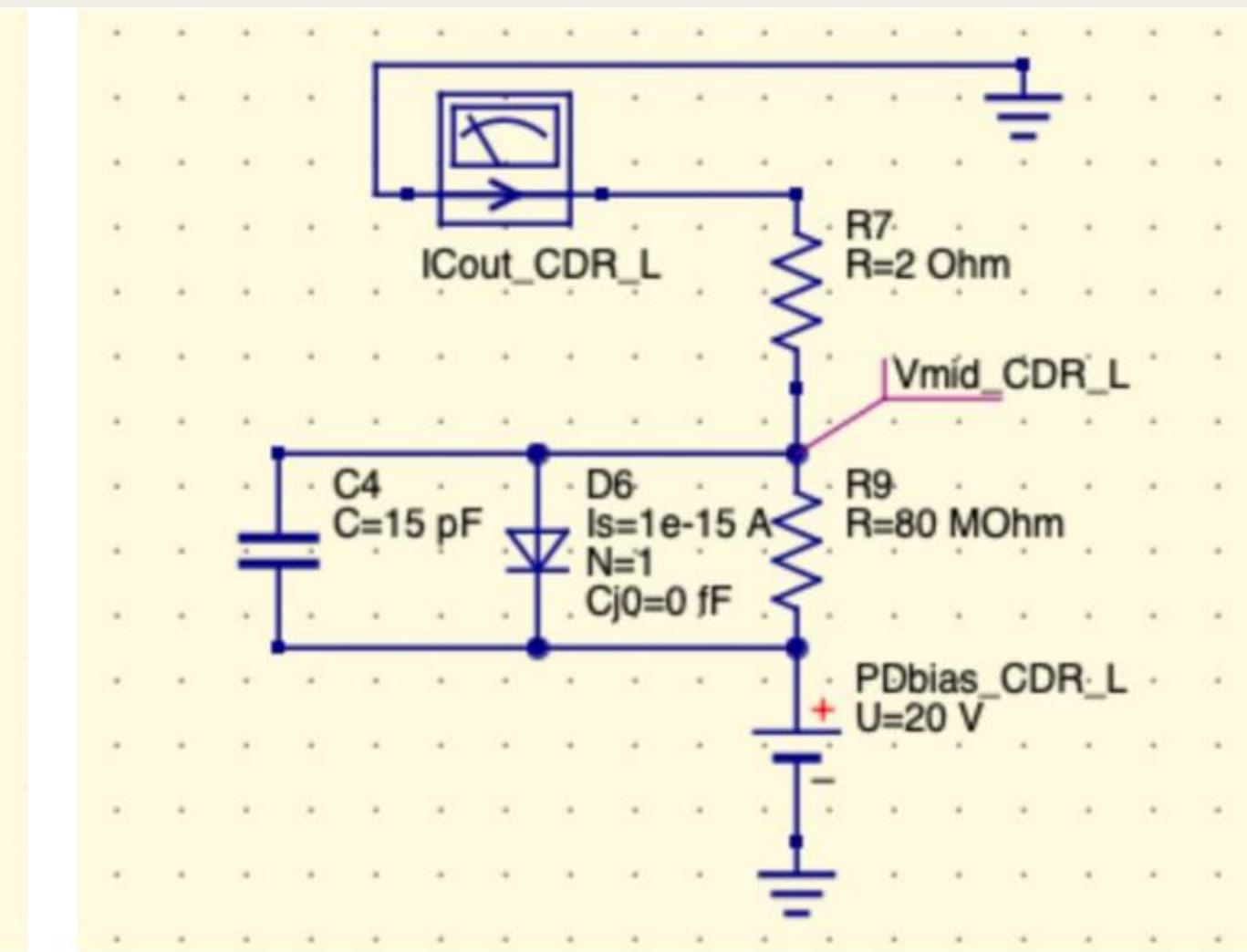
Thanks for the
attention!



SIMULATION



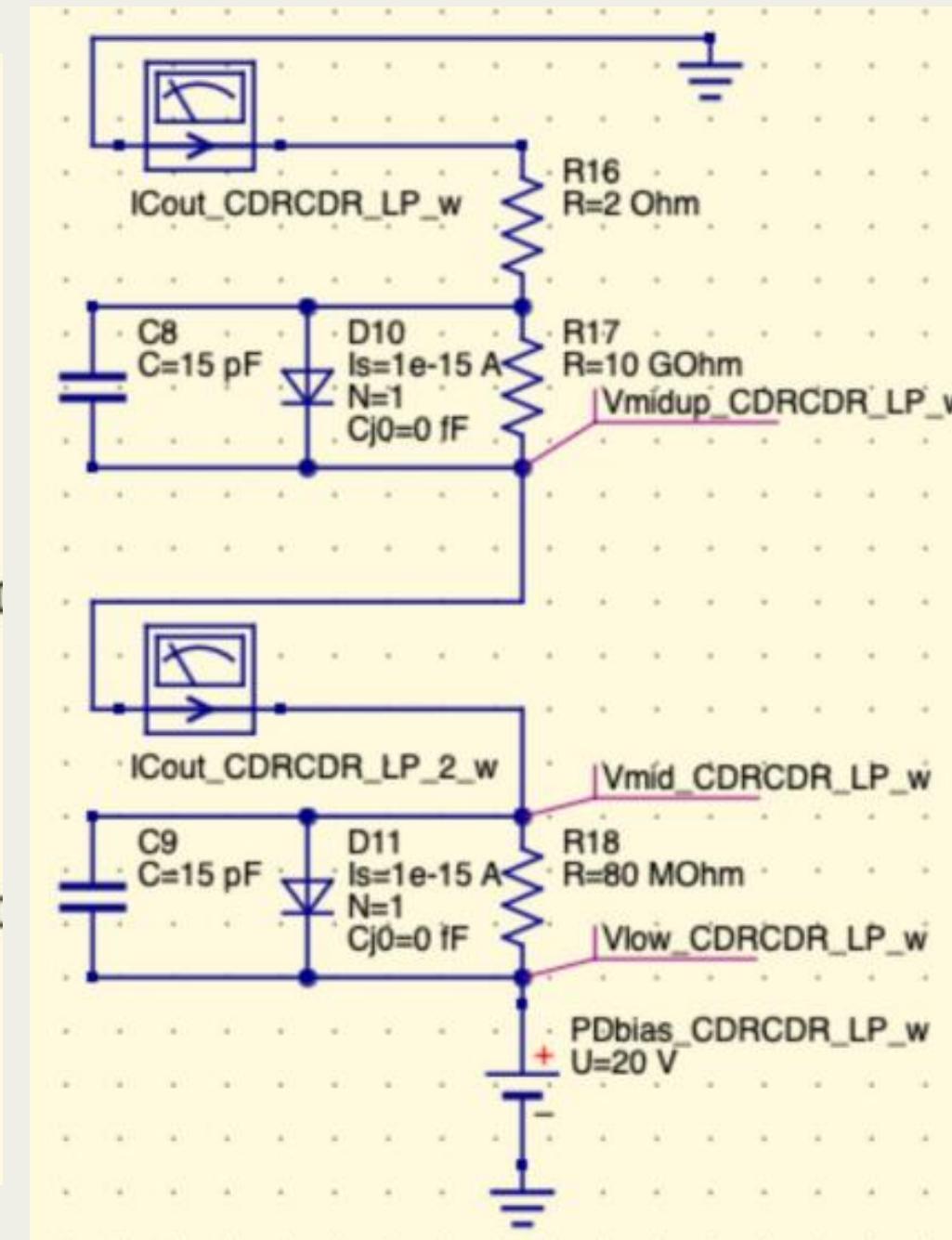
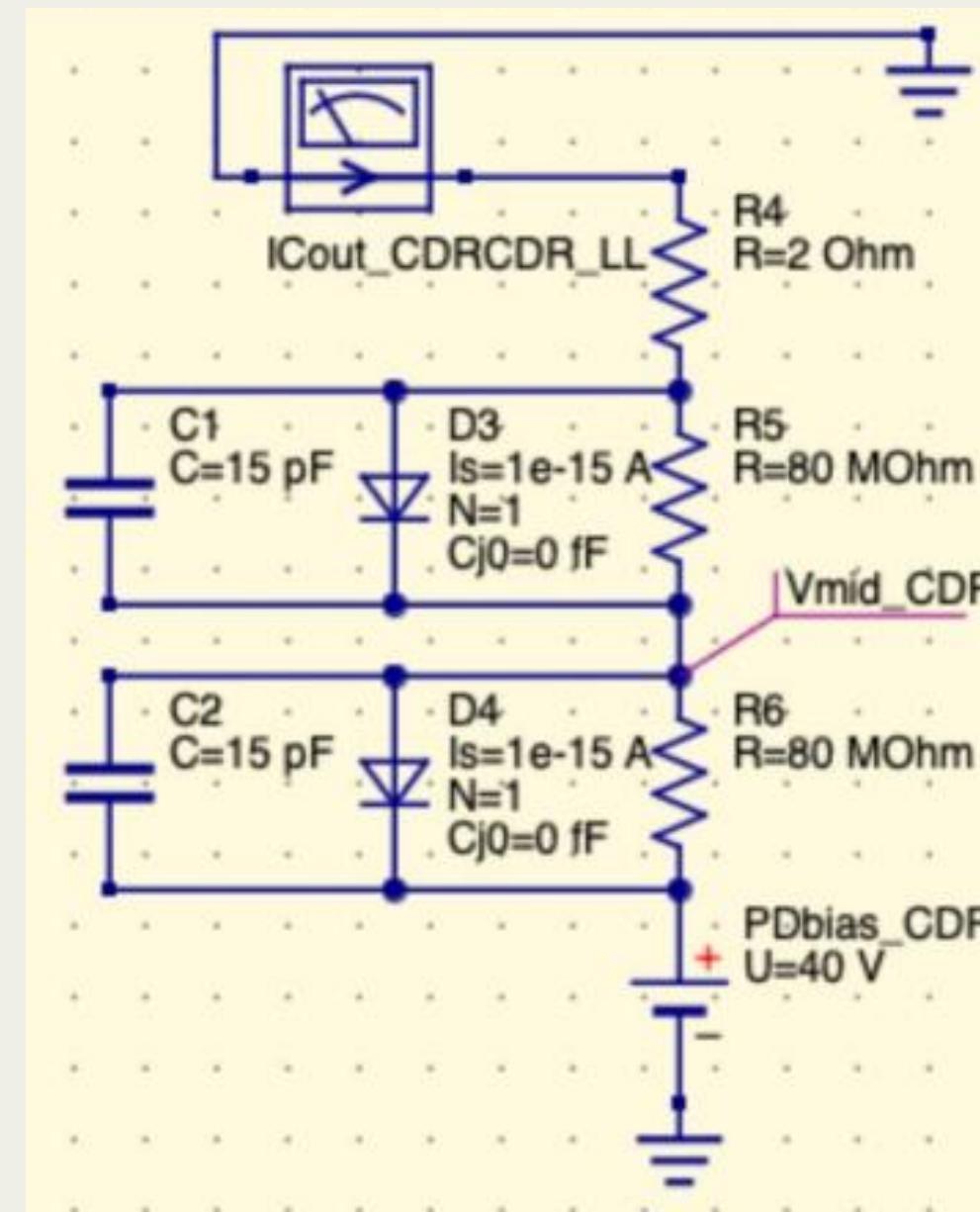
Circuit diagram of a PIN



Circuit diagram of an LGAD

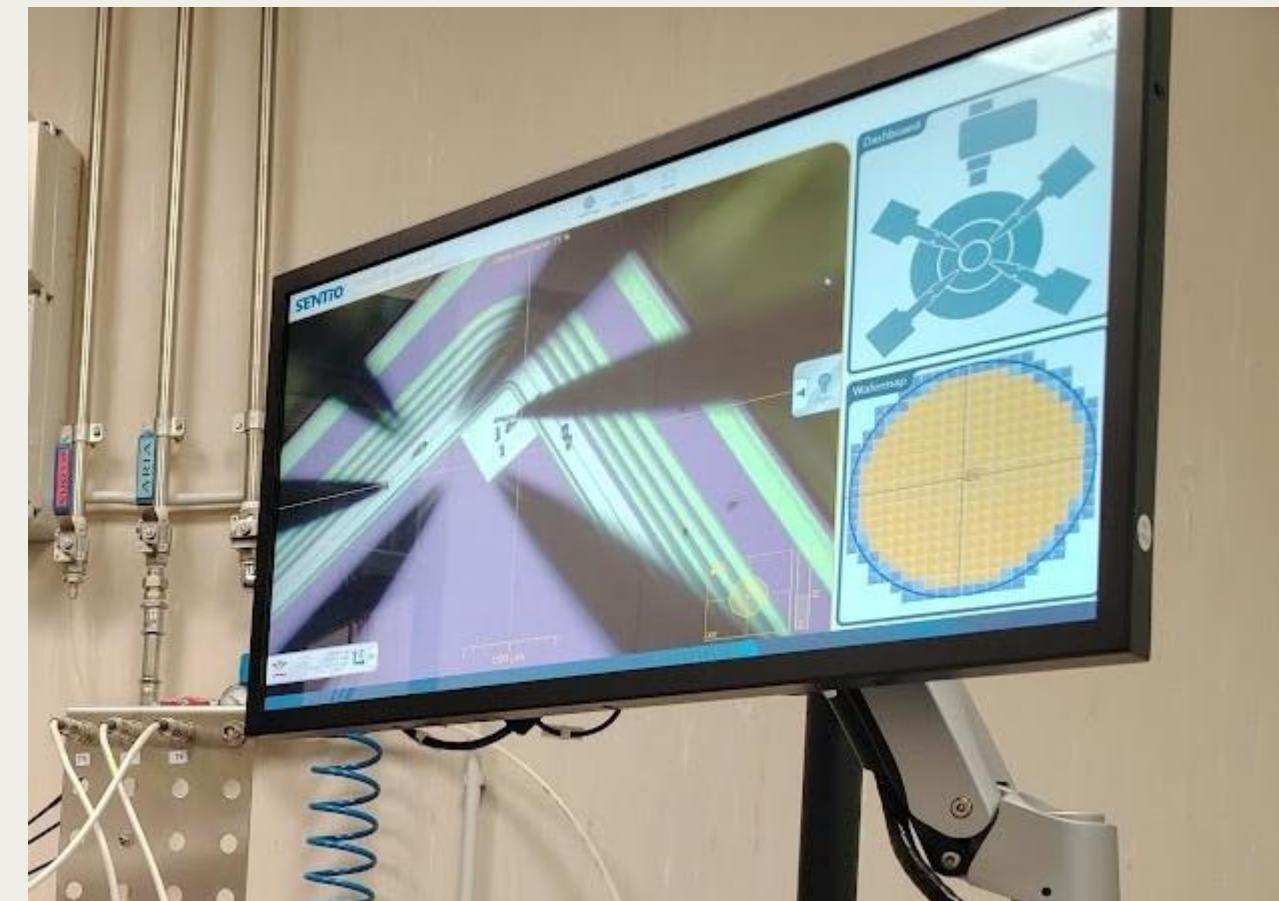
SIMULATION

Circuit diagram
of the LGAD-
LGAD couple



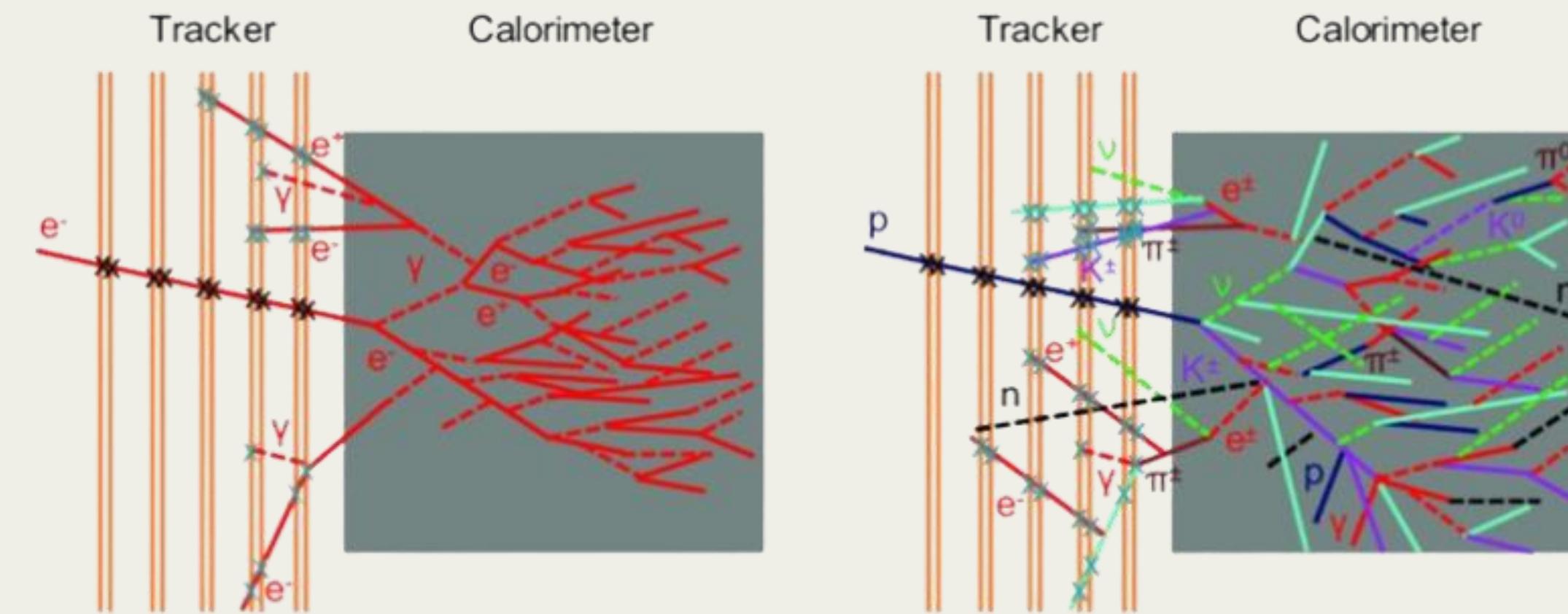
Circuit diagram
of the LGAD-
PIN couple

PROBE STATION



Probe station used in the
Perugia's Clean Room

IMPROVEMENTS ENABLED BY TEMPORAL MEASUREMENTS



Improvements that temporal measurements can implement:

- They can be complementary to those performed by ToF (on the order of picoseconds).
- They improve the identification of particle trajectories in environments with a high interaction rate.
- They help remove ghost hits by better separating the signals received by the strips.

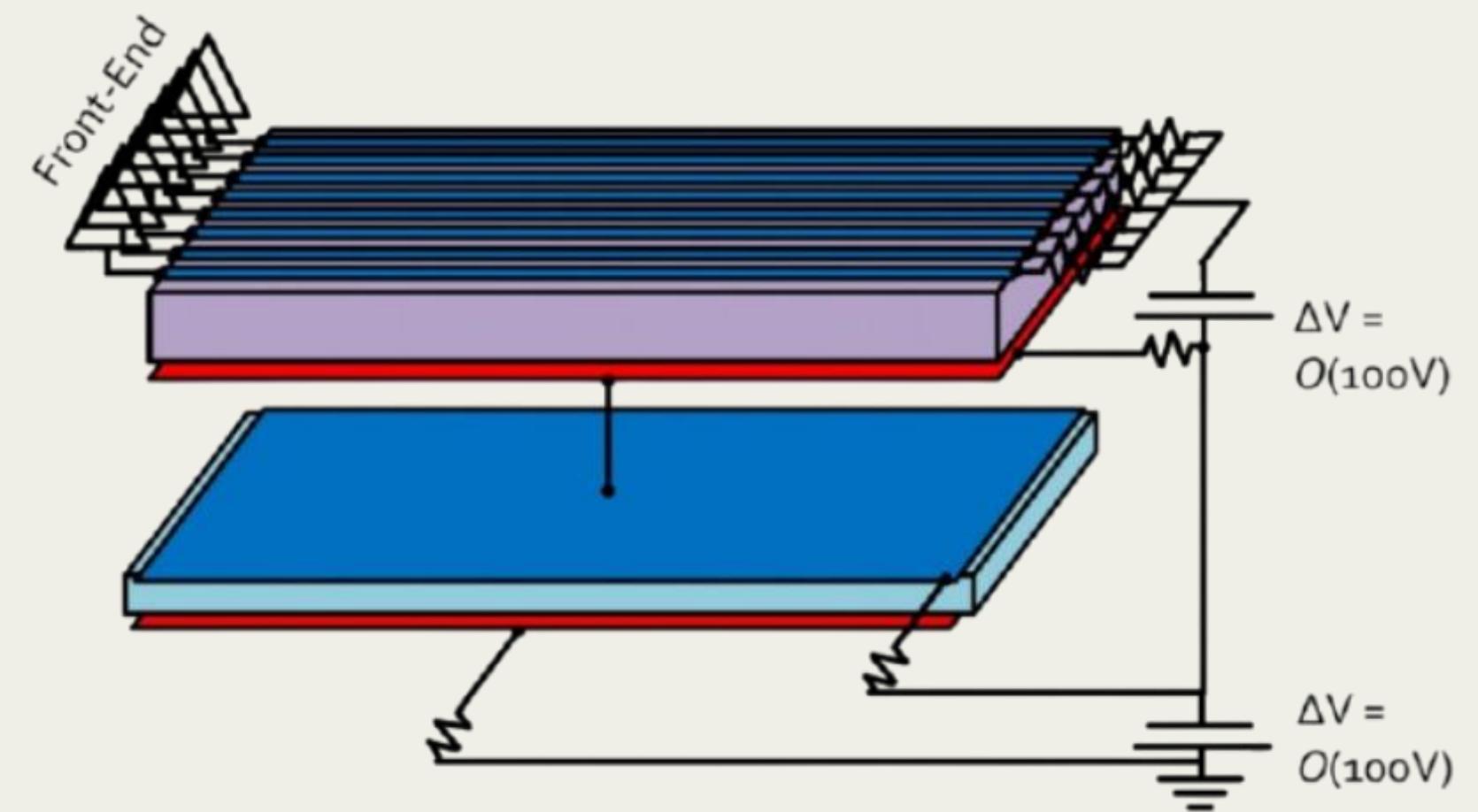
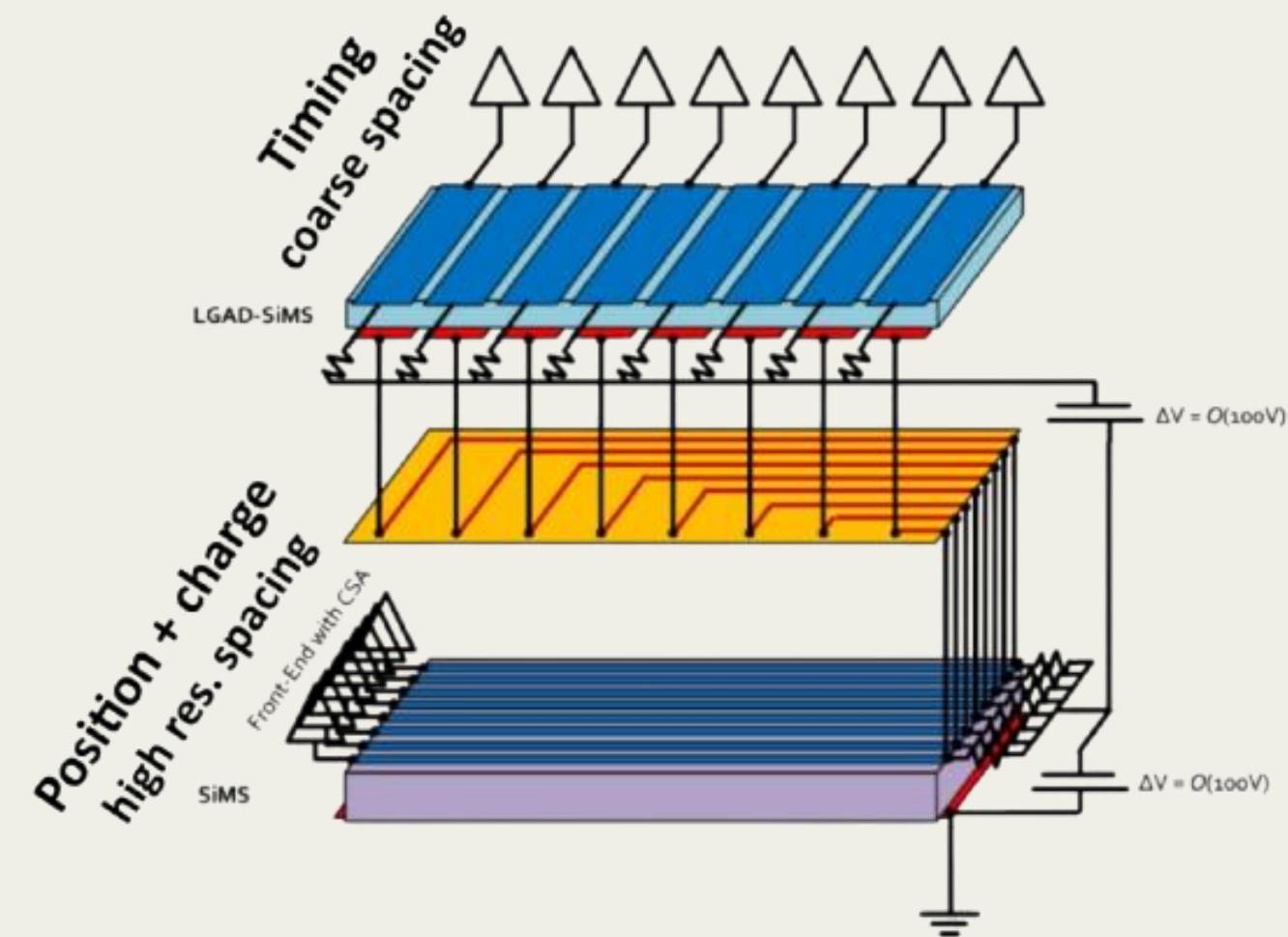
NOISE SOURCES

Other noise sources include:

- **Jitter:** fluctuations in time measurement due to electronic noise.
- **Ionization:** statistical variations in the primary charge generation process.
- **Signal distortion:** alterations of the signal during transport and readout.
- **TDC:** uncertainty arising from the fact that the TDC, having a finite number of bins, discretizes the signal.

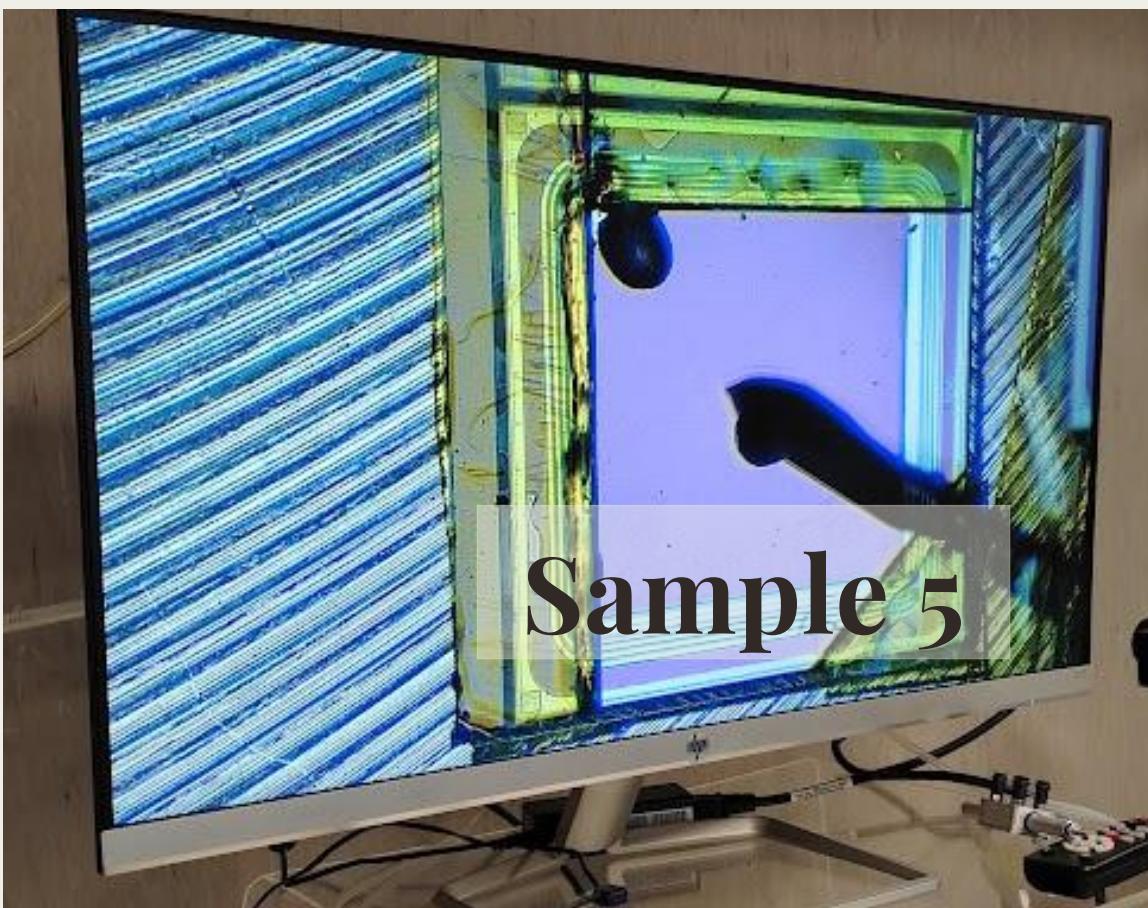


FUTURE POSSIBILITY



Possibility for future devices

EXPERIMENTAL SETUP



Two devices (sample 3 and sample 5) had been glued together with two little drops of connective glue

